

HIGH-VOLTAGE HIGH-CURRENT DARLINGTON TRANSISTOR ARRAYS

ILN2003A

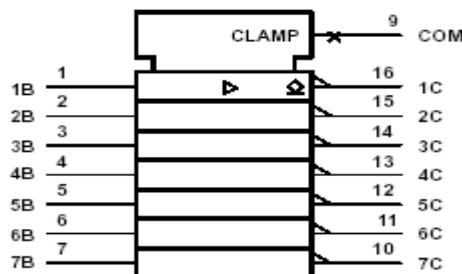
The ILN2003A are monolithic high-voltage, high-current Darlington transistor arrays. Each consists of seven n-p-n Darlington pairs that feature high-voltage outputs with common-cathode clamp diodes for switching inductive loads. The collector-current rating of a single Darlington pair is 500 mA. The Darlington pairs may be paralleled for higher current capability. Applications include relay drivers, hammer drivers, lamp drivers, display drivers (LED and gas discharge), line drivers, and logic buffers.

The ILN2003A has a 2.7-k Ω series base resistor for each Darlington pair for operation directly with TTL or 5-V CMOS devices.

- 500-mA Rated Collector Current (Single Output)
- High-Voltage Outputs . . . 50 V
- Output Clamp Diodes
- Inputs Compatible With Various Types of Logic
- Relay Driver Applications
- Ordering Information

Operation Temperature	PKG Type	Ordering part number
-40°C ~ 85°C	DIP - 16	ILN2003AN
	SOP - 16	ILN2003ADT
-40°C ~ 105°C	DIP - 16	ILN2003AIN
	SOP - 16	ILN2003AIDT

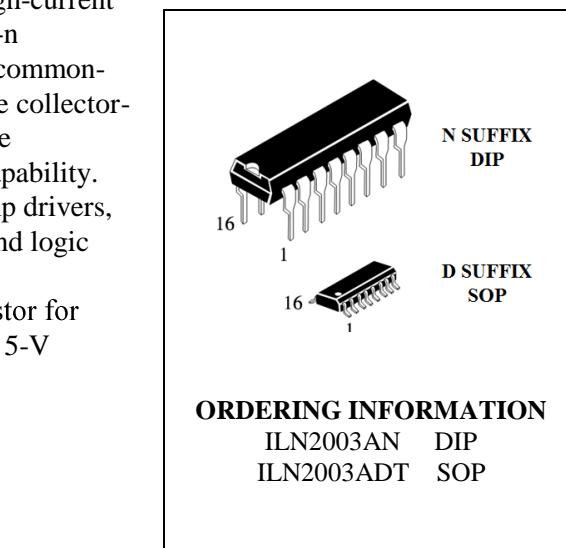
LOGIC SYMBOL



SCHEMATICS (each Darlington Pair)

All resistor values shown are nominal.

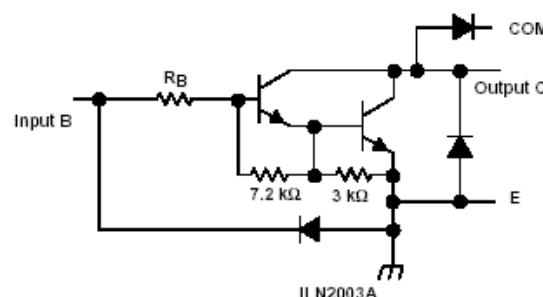
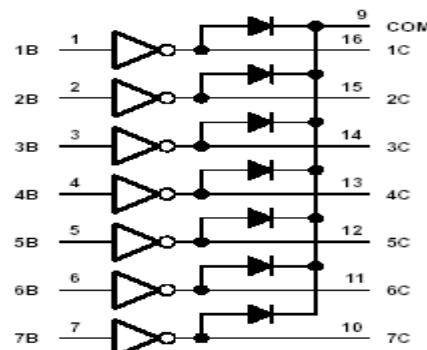
ILN2003A: $R_B = 2.7 \text{ k}\Omega$



ORDERING INFORMATION

ILN2003AN	DIP
ILN2003ADT	SOP

LOGIC DIAGRAM



Absolute Maximum Ratings (Ta =25°C)

Parameter	Symbol	Limit Values		Unit
		min.	max.	
Output Sustaining Voltage	V _{CE(SUS)}	-0.5	50	V
Output Current	I _{OUT}	500		mA/ch
Input Voltage	V _{IN}	-0.5	30	V
Clamp Diode Reverse Voltage	V _R	50		V
Clamp Diode Forward Current	I _F	500		mA
Power Dissipation	DIP	1.15		W
	SOP	0.95		
Operating Temperature	T _{opr}	-40	85	°C
Storage Temperature	T _{stg}	-55	150	°C

* Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

Recommended Operating Conditions
(Ta=-40~85°C)

Parameter	Symbol	Test Condition	Limit Value			Unit
			Min	Typ	Max	
Output Sustaining Voltage	V _{CE(SUS)}		0	-	50	V
Output Current	DIP	T _{pw} =25ms,Duty=10%, 7 Circuits	0	-	370	mA/ch
		T _{pw} =25ms,Duty=30%, 7 Circuits	0	-	200	
		T _{pw} =25ms,Duty=10%, 7 Circuits	0	-	290	
		T _{pw} =25ms,Duty=30%, 7 Circuits	0	-	150	
Input Voltage	V _{IN}		0	-	30	V
Clamp Diode Reverse Voltage	V _R		-	-	50	V
Clamp Diode Forward Current	I _F		-	-	400	mA
Power Dissipation	DIP		-	-	0.52	W
	SOP		-	-	0.4	

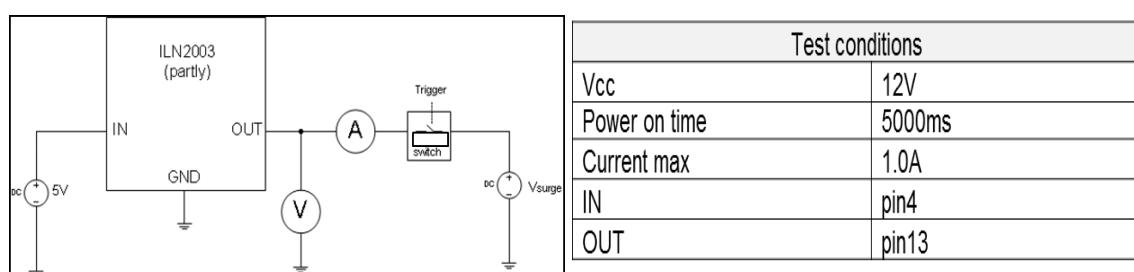
Electrical characteristics, $T_A = 25^\circ\text{C}$ (unless otherwise noted)

Parameter	Test Fig.	Test Conditions	Min	Typ	Max	Unit	
$V_{I(on)}$ On-state Input Voltage	6	$V_{CE}=2\text{V}$	$I_C=125\text{mA}$			V	
			$I_C=200\text{mA}$		2.4		
			$I_C=250\text{mA}$		2.7		
			$I_C=275\text{mA}$				
			$I_C=300\text{mA}$		3		
			$I_C=350\text{mA}$				
$V_{CE(sat)}$ Collector-emitter saturation voltage	5	$I_I=250\text{\mu A}$	$I_C=100\text{mA}$	0.9	1.1	V	
		$I_I=350\text{\mu A}$	$I_C=200\text{mA}$	1	1.3		
		$I_I=500\text{\mu A}$	$I_C=350\text{mA}$	1.2	1.6		
I_{CEX} Collector outoff current	1	$V_{CE}=50\text{V}$	$I_I=0$		50	uA	
	2	$V_{CE}=50\text{V}, T_A=85^\circ\text{C}$	$I_I=0$		100		
h_{FE} DC Current Transfer Ratio	5	$V_{CE}=2\text{V}, I_{OUT}=350\text{mA}$		1000	-	-	
V_F Clamp forward voltage	8	$I_F=350\text{mA}$			1.7	2	V
$I_{I(off)}$ Off-state input current	3	$V_{CE}=50\text{V}$ $T_A=85^\circ\text{C}$	$I_C=500\text{\mu A}$	50	65		uA
I_I Input current	4	$V_I=2.4\text{V}$			0.4	0.7	mA
		$V_I=5\text{V}$					
		$V_I=12\text{V}$					
I_R Clamp reverse current	7	$V_R=50\text{V}$			50	uA	
		$V_R=50\text{V}$	$T_A=85^\circ\text{C}$		100		
C_I Input capacitance		$V_I=0$	$f=1\text{MHz}$		15	25	pF

Switching Characteristics, $T_A=25^\circ\text{C}$

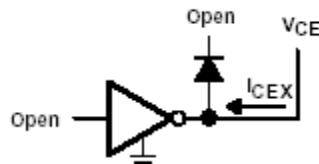
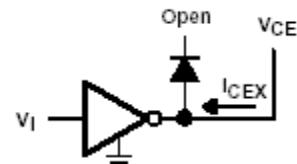
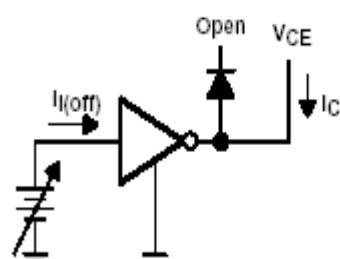
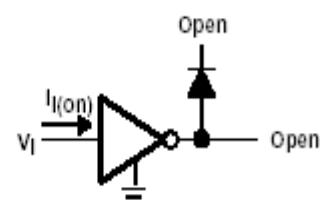
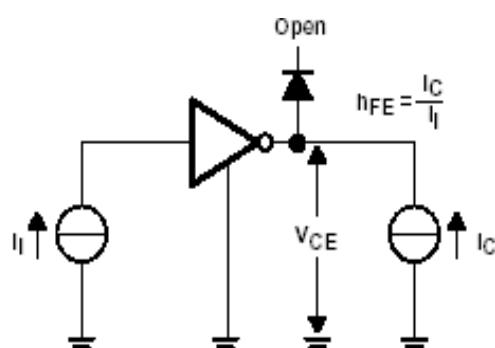
Parameter	Test Conditions	Min	Typ	Max	Unit
t_{PLH} Propagation delay time, low-to-high-level output	See Figure 9		0.25	1	us
t_{PHL} Propagation delay time, high -to- low -level output			0.25	1	us
V_{OH} High-level output voltage after switching	$V_S=50\text{V}, I_O=300\text{mA},$ See Figure 10	V_S-20			mV

* EOS (Electrical Over Stress) Immunity Level
Test Circuit

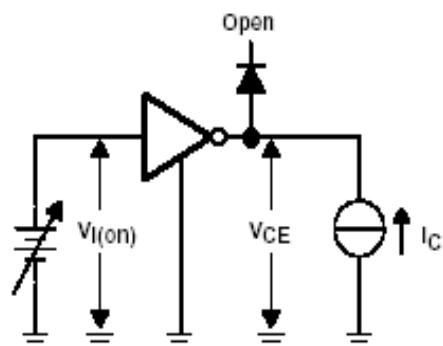


tE (Endurance time) : time until IC damage / Criterion : IC should survive EOS
EOS Immunity Level: More than 5000ms

PARAMETER MEASUREMENT INFORMATION

Figure 1. I_{CEx} Test CircuitFigure 2. I_{CEx} Test CircuitFigure 3. $I_{I(off)}$ Test CircuitFigure 4. I_I Test Circuit

NOTE: I_I is fixed for measuring $V_{CE(sat)}$, variable for measuring h_{FE} .

Figure 5. h_{FE} , $V_{CE(sat)}$ Test CircuitFigure 6. $V_{I(on)}$ Test Circuit

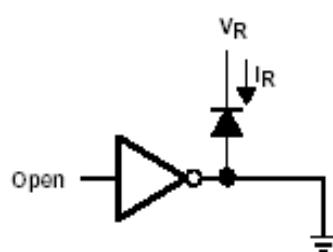
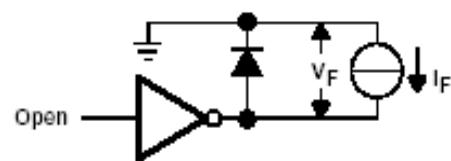
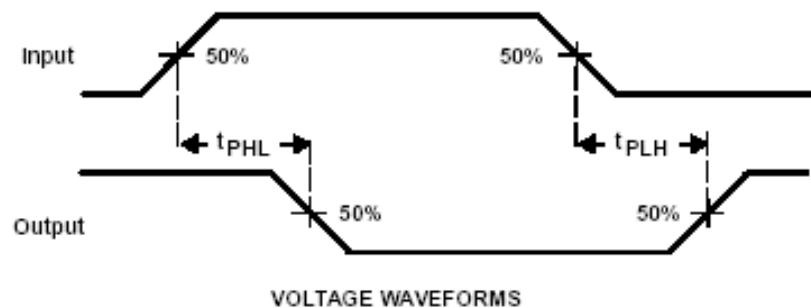
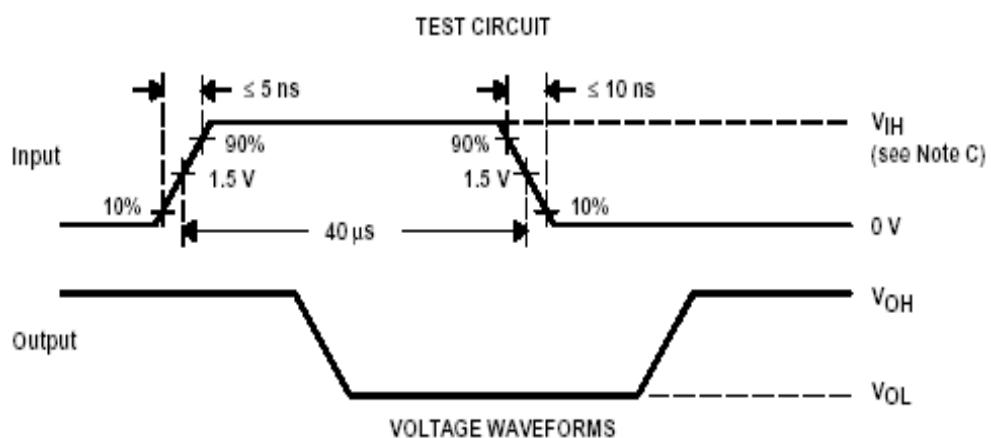
Figure 7. I_R Test CircuitFigure 8. V_F Test Circuit

Figure 9. Propagation Delay-Time Waveforms



NOTES: A. The pulse generator has the following characteristics: PRR = 12.5 kHz, $Z_0 = 50 \Omega$.

- B. C_L includes probe and jig capacitance.
- C. $V_{IH} = 3$ V;

Figure 10. Latch-Up Test Circuit and Voltage Waveforms

TYPICAL CHARACTERISTICS

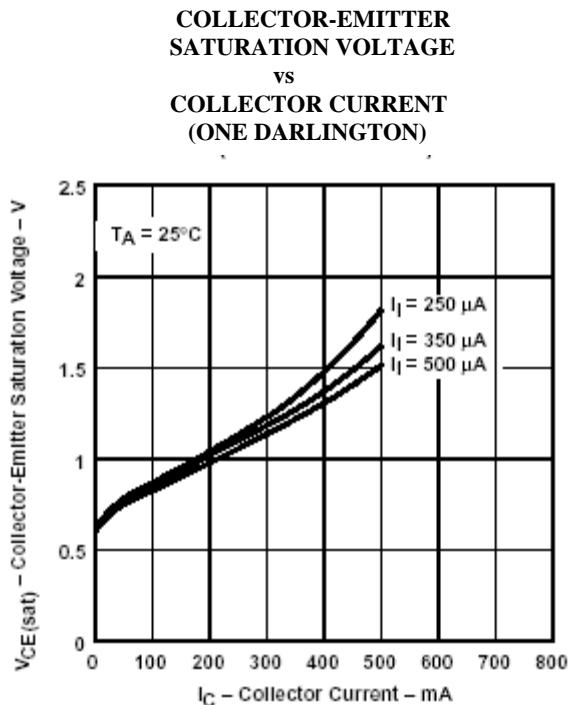


Figure 11

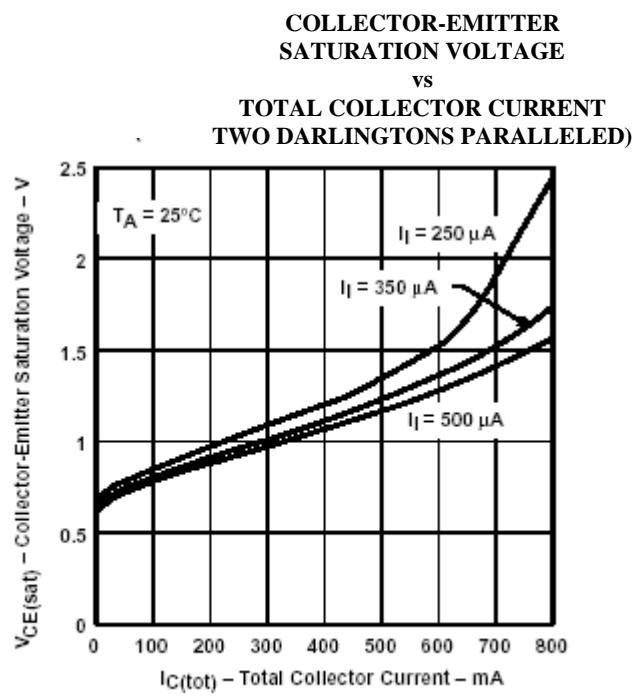


Figure 12

COLLECTOR CURRENT vs

INPUT CURRENT

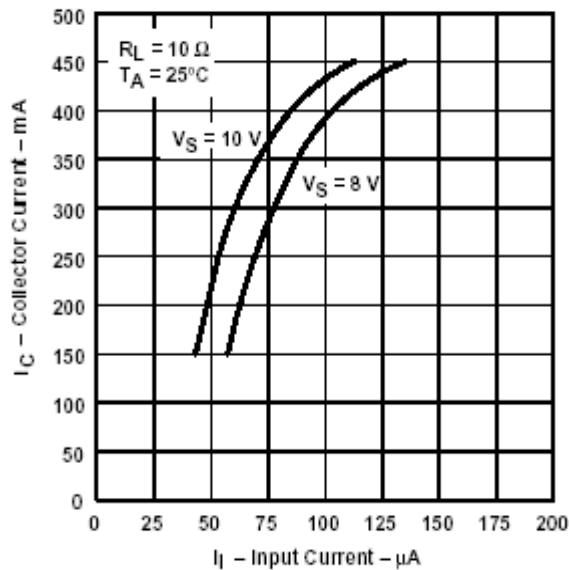


Figure 13

THERMAL INFORMATION

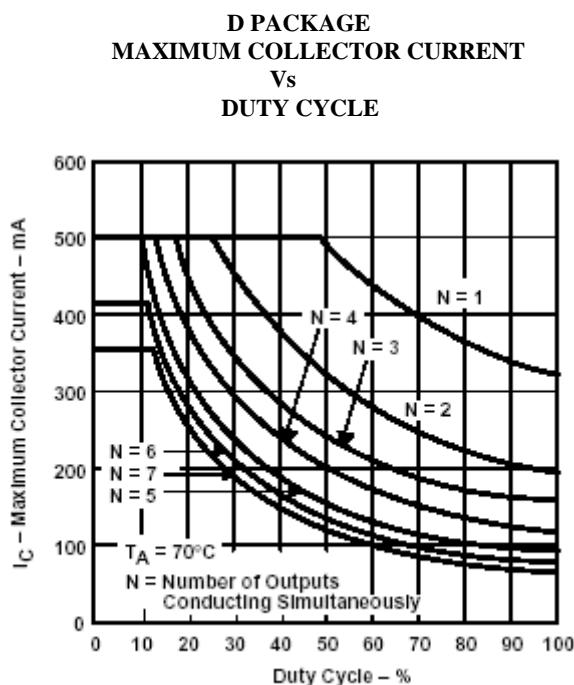


Figure 14

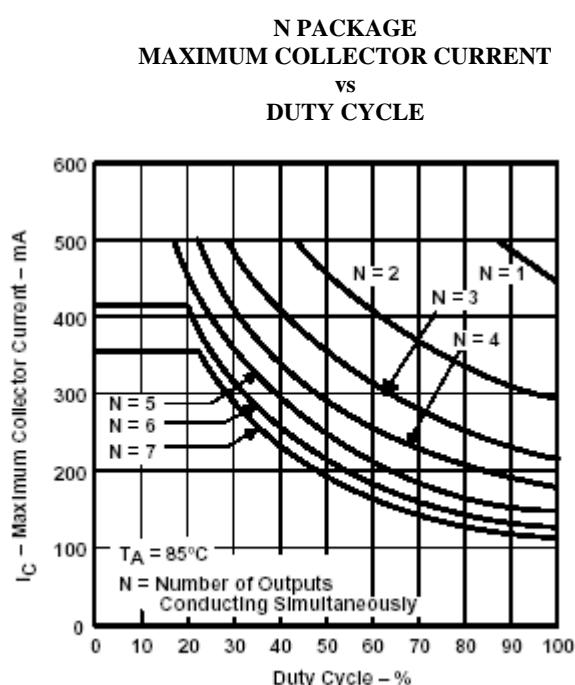
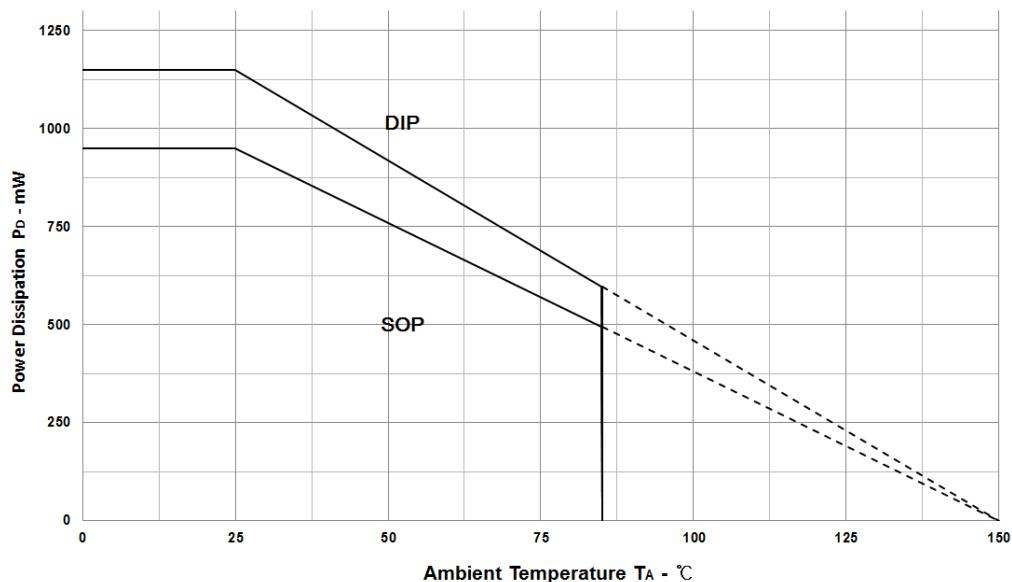


Figure 15

POWER DISSIPATION

VS.
AMBIENT TEMPERATURE



APPLICATION INFORMATION

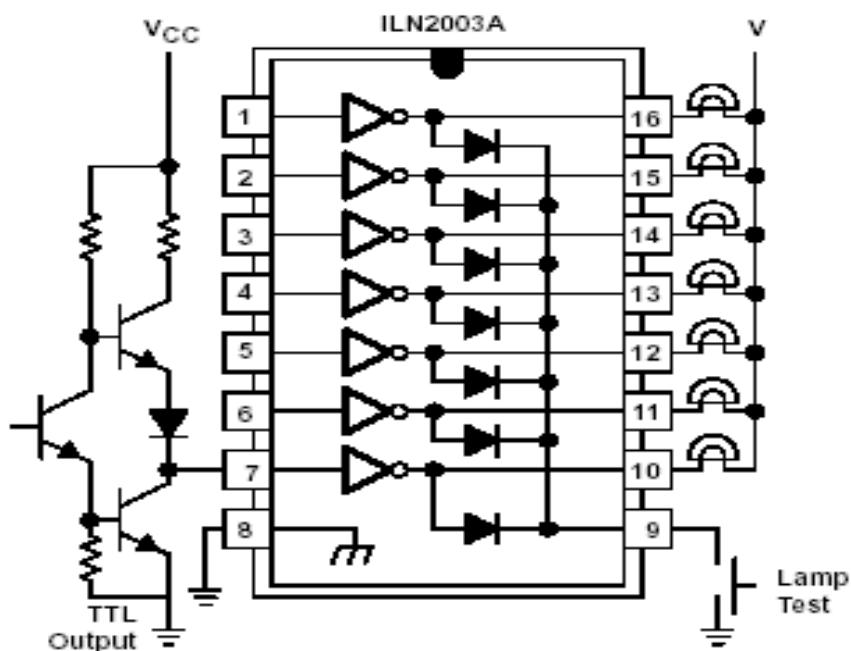


Figure 16. TTL to Load

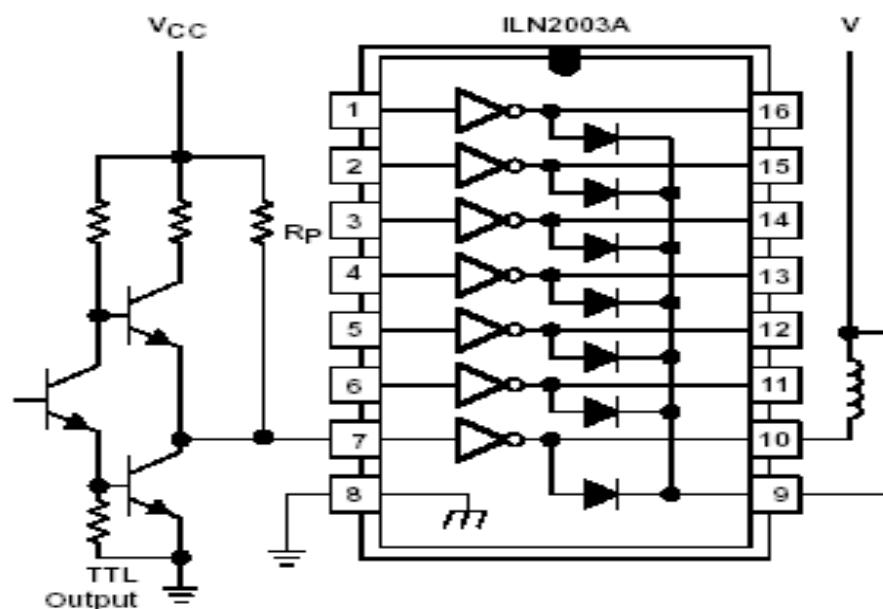
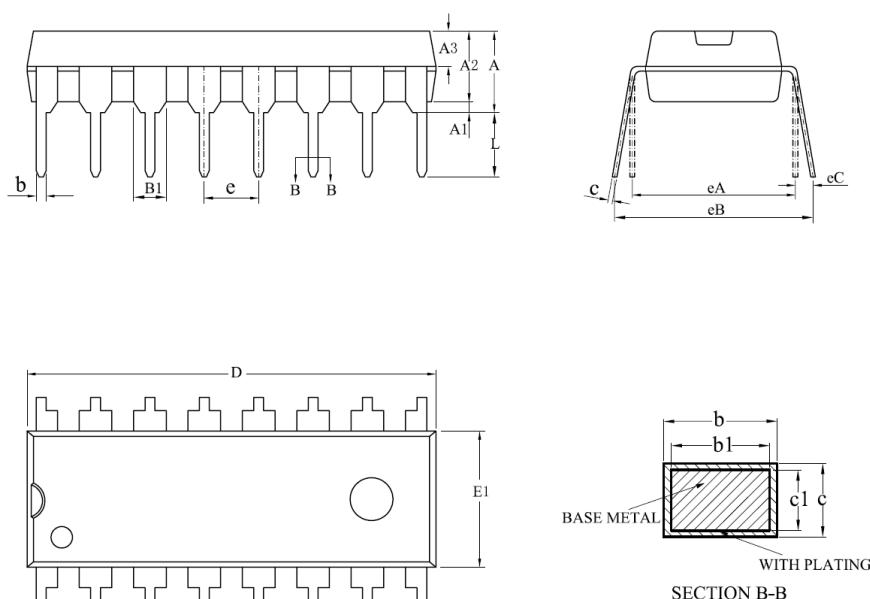
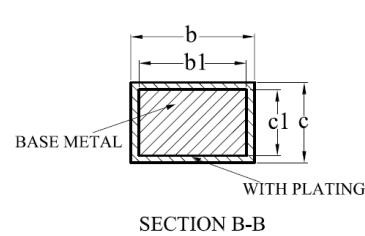
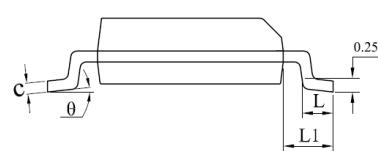
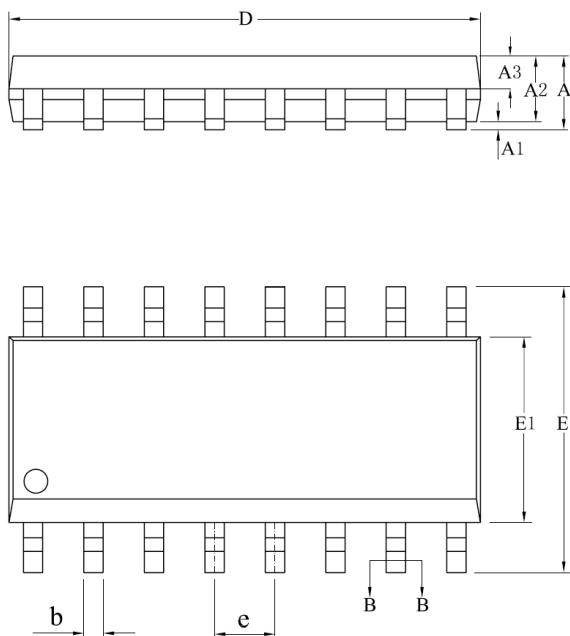


Figure 17. Use of Pullup Resistors to Increase Drive Current

DIP-16



SOP-16



SYMBOL	MILLIMETER		
	MIN	NOM	MAX
A	—	—	1.75
A1	0.10	—	0.25
A2	1.35	1.40	1.45
A3	0.60	0.65	0.70
b	0.39	—	0.48
b1	0.38	0.41	0.43
c	0.21	—	0.26
c1	0.19	0.20	0.21
D	9.70	9.90	10.10
E	5.80	6.00	6.20
E1	3.70	3.90	4.10
e	1.27BSC		
L	0.50	—	0.80
L1	1.05BSC		
θ	0	—	8°
75*75			
90*110			
90*180			